

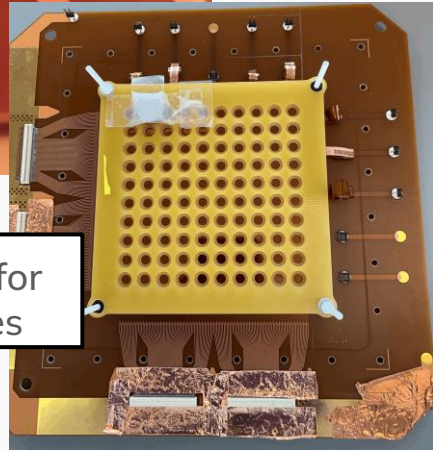
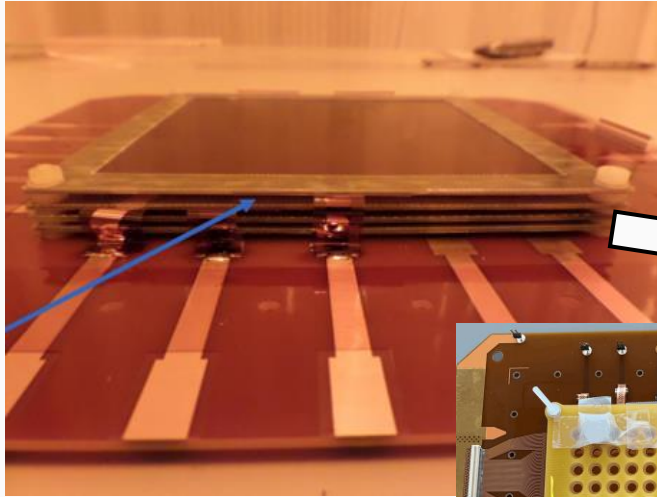
GORG



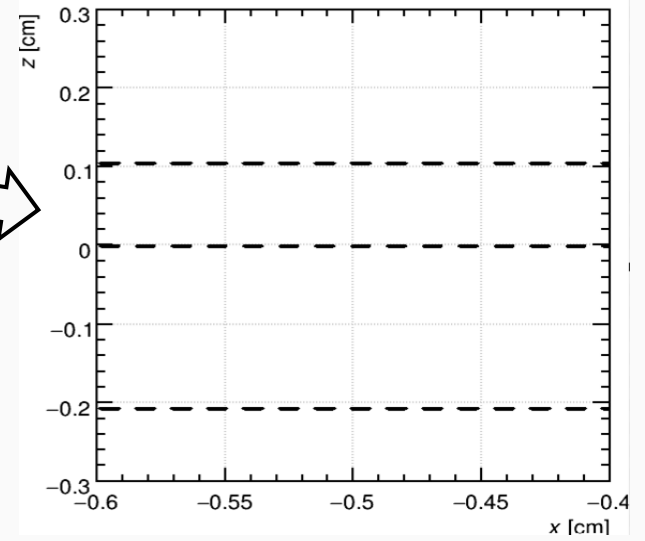
Simulation Studies

ND-GAr Meeting Update 12/17/2024

Recap: GEM Simulations



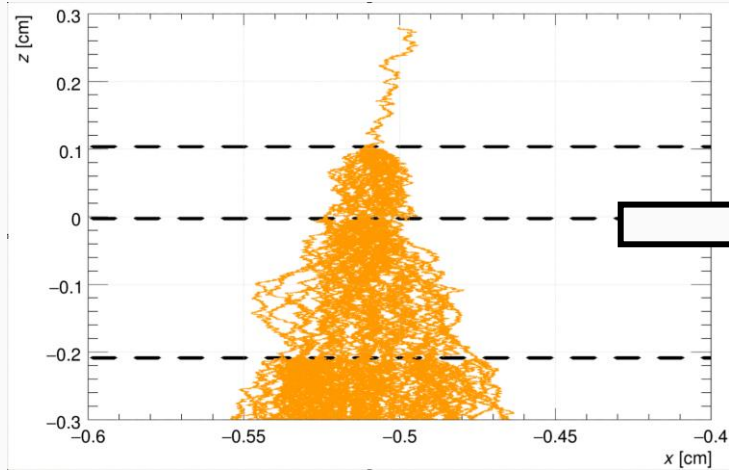
Developed framework for GEM simulation studies



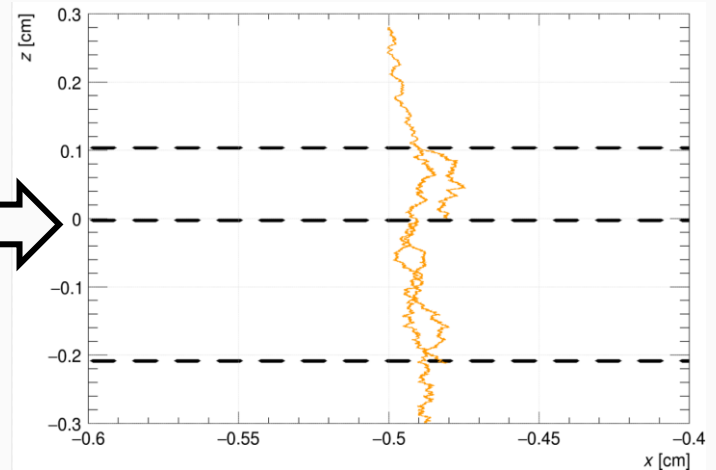
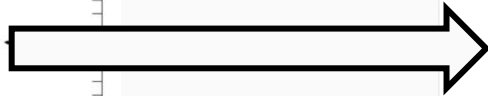
Garfield++ can simulate microphysics in GEM structures



Previous Results: GEMs in High Pressure



Avalanche – **Ar:Co2 80:20, 1 atm**



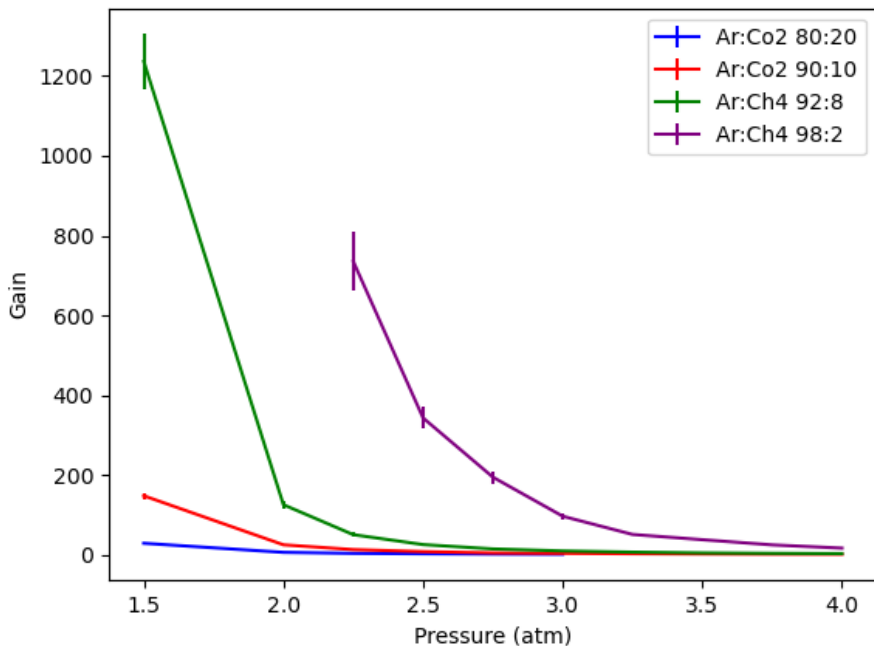
Avalanche – **Ar:Co2 80:20, 2 atm**

Increasing the pressure decreases mean free path of electron → **reduces gain**



Previous Results: Effect of Gas Mixture

Gain in Triple GEM at High Pressures: Garfield++ Simulation



Ar:Ch₄ 98:2 outperforms other gas mixtures for sustaining gain

Note: plot is for unoptimized parameters:

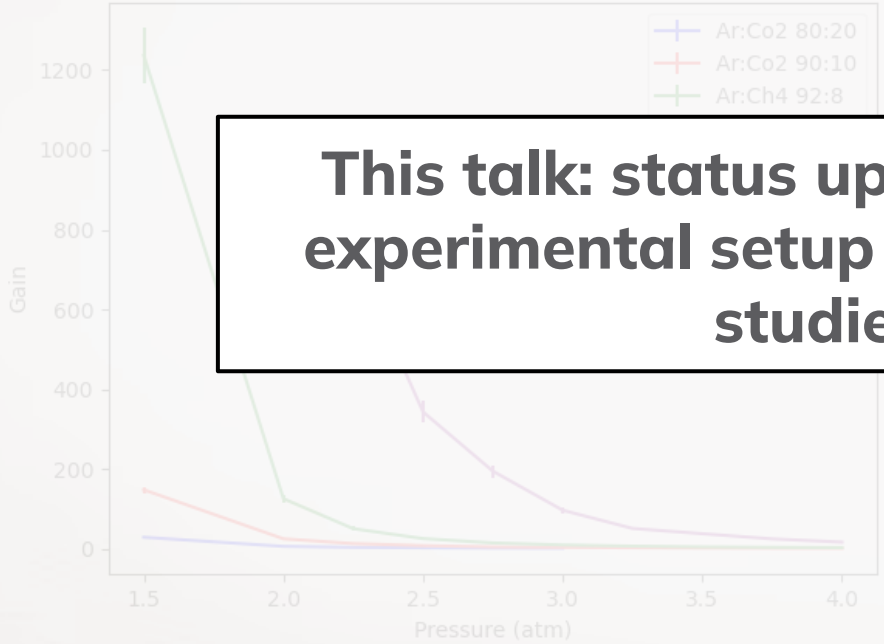
~350V supplied to GEM1

~ETI \approx 6.0kV/cm



Recap: Effect of Gas Mixture

Gain in Triple GEM at High Pressures: Garfield++ Simulation

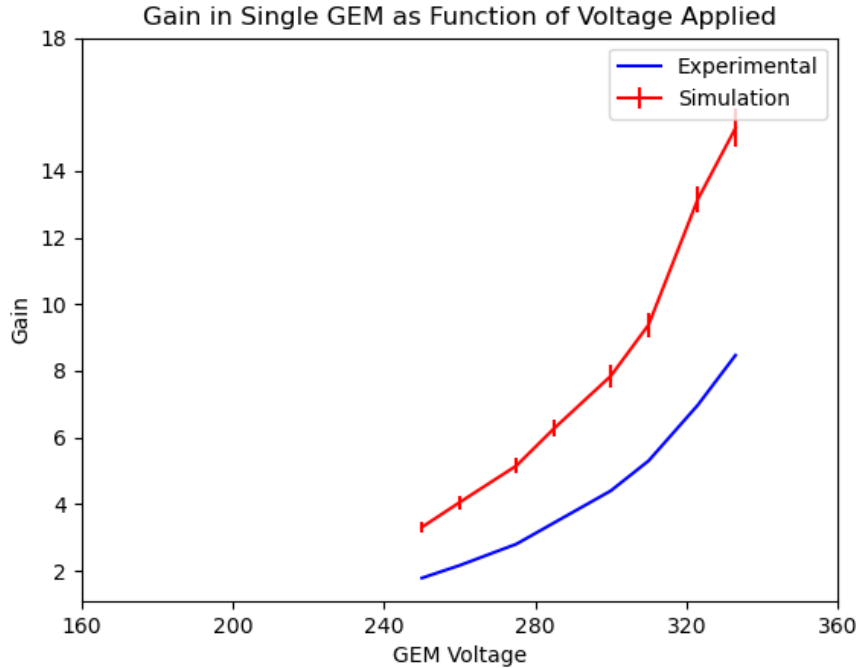


Ar:Ch4 98:2 outperforms other gas mixtures for sustaining gain

This talk: status update on GORG experimental setup and simulation studies

GEM1 ~350V supplied to

Benchmarking: Voltage Applied



Ar:Co2 80:20, 1 atm

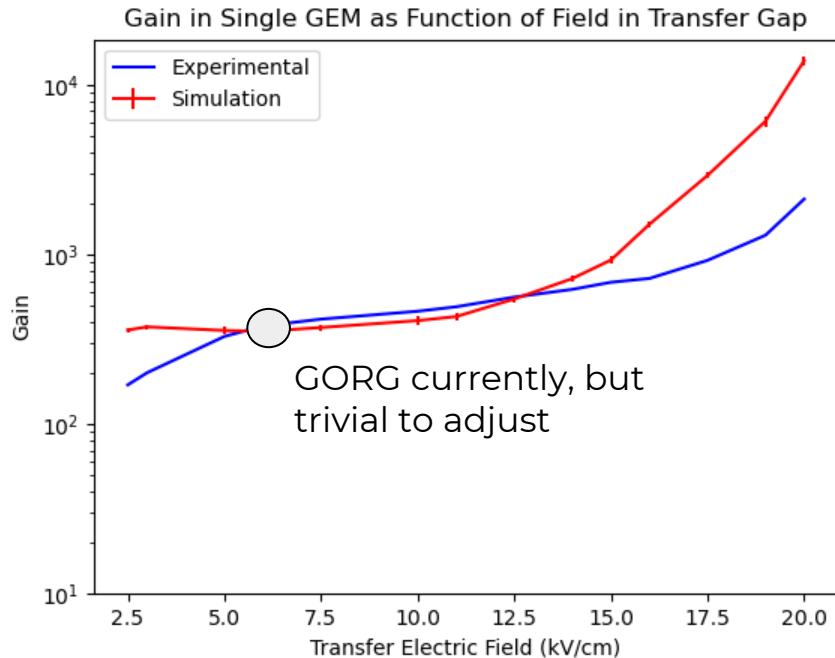
- ★ Simulation results overestimate but agree within a factor of 2
- Experimental data from:

High Energy Phys. 2016, 8561743. DOI: [10.1155/2016/8561743](https://doi.org/10.1155/2016/8561743)

$\sim E_1 = 1\text{kV/cm}$

\sim Induction gap = 8.5mm

Benchmarking: Electric Field Strength



- ★ For a single GEM with:
 - Ar:CO₂ 70:30** 1 atm
 - 500V across GEM
 - 0.5mm induction gap

demonstrates up to an **18-fold increase in gain!**

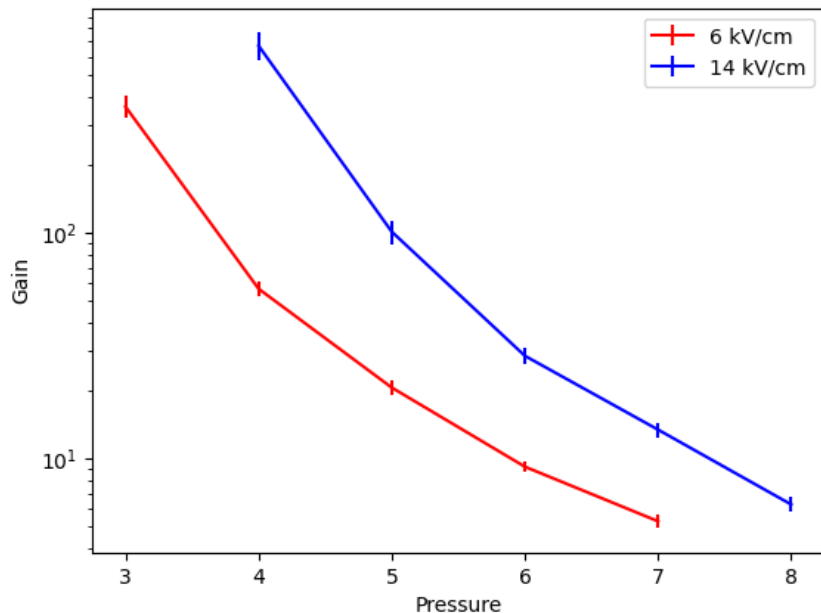
Experimental results from:

A. Bondar, et al., Nuclear Instruments and Methods A 419 (1998) 418.



GORG Simulations: Electric Field Strength

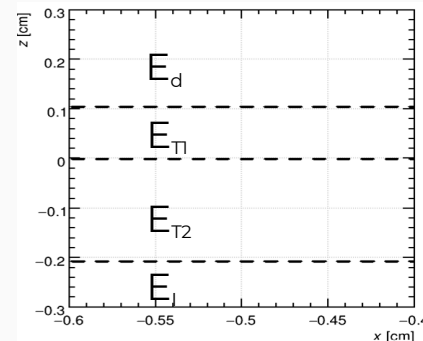
GORG Triple-GEM Gain : Modifying Electric Field Strength



Ar:Ch4 98:2 , 500V to GEM1

- Electric field strength modified only in transfer gap between GEM1 and GEM2:

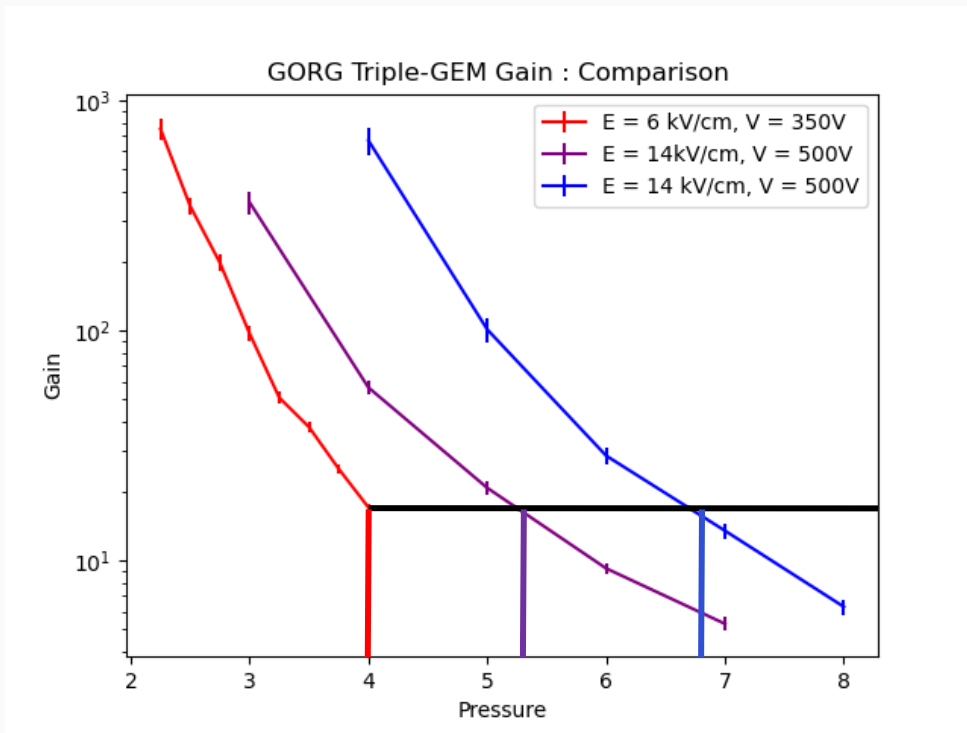
$E_d \sim 2.5$ kV/cm
 $E_{T2} \sim 3.0$ kV/cm
 $E_1 \sim 6.0$ kV/cm



- **an increased 500V to GEM1**
- Can increase achievable gain at high pressures!



Comparison with Previous Results



Ar:Ch4 98:2

$E_d \sim 2.5 \text{ kV/cm}$

$E_{T2} \sim 3.0 \text{ kV/cm}$

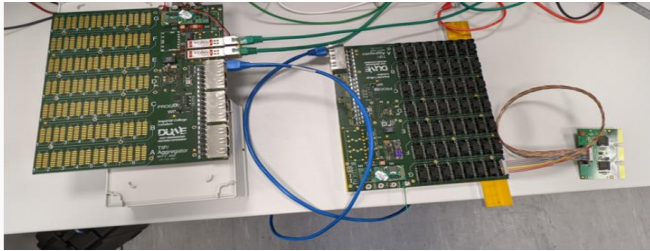
$E_I \sim 6.0 \text{ kV/cm}$

- Achieve similar gains at $\sim +3 \text{ atm}$!
- More to optimize:
 - Transfer gaps
 - GEM geometry: pitch, thickness, hole diameter

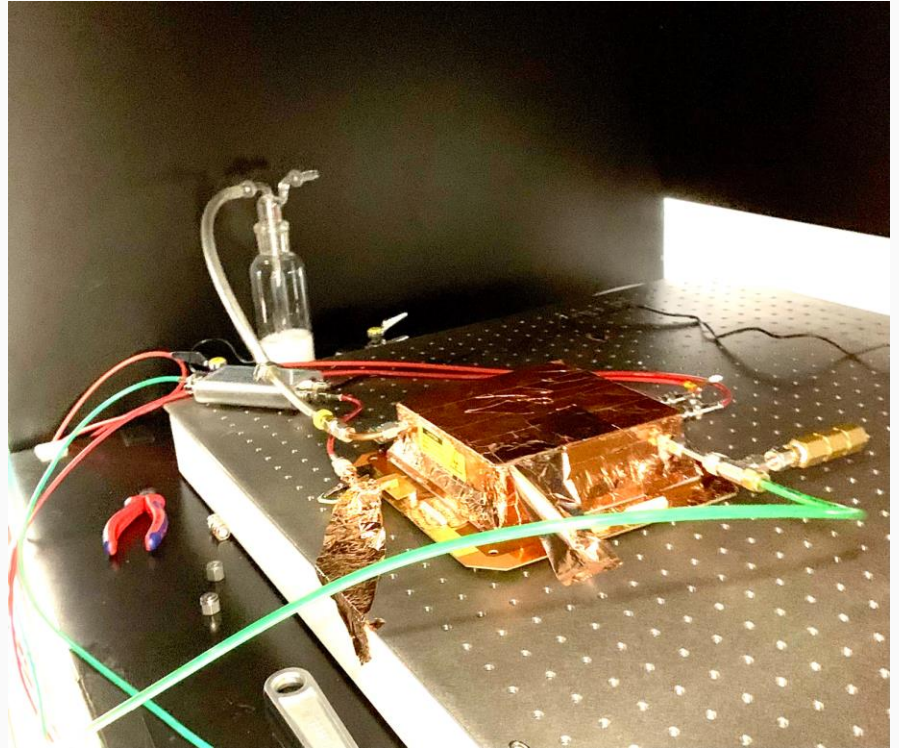
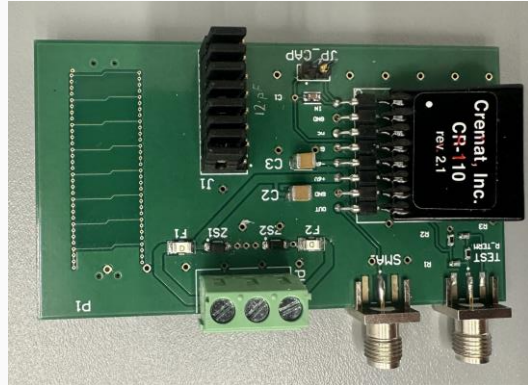


Electronics Upgrades Underway

Full chain of electronics under development by Imperial colleagues



Low Noise Cremat II Card being tested at FNAL





Summary

- Benchmarked simulation results with established experimental data
- Evaluated the effect of electric field strength on GEM gain
 - Other parameters that can be optimized in simulation to further increase gain:
 - Transfer gaps
 - GEM pitch
 - GEM hole diameter
- Progress experimentally in electronics upgrades; preparing for pressure vessel operation at Fermilab, setup underway at Indiana University!